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 Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These devices are 14-stage binary ripple-carry counters that advance on the negative-going edge of the clock pulse. The counters are reset to zero (all outputs low) independently of the clock (CLK) input when the clear (CLR) input goes high.

The SN54HC4020 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74HC4020 is characterized for operation from -40° C to 85°C.

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, N, and W packages.



SN54HC4020 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection



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logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	113°C/W
N package	
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

			SN	54HC40	HC4020 SN74HC40			20	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
VIH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		ACC = 6 A	4.2			4.2			
		$V_{CC} = 2 V$	0		0.5	0		0.5	
VIL	Low-level input voltage	V _{CC} = 4.5 V	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 2 V$	0		1000	0		1000	
^t t	Input transition (rise and fall) time	$V_{CC} = 4.5 V$	0		500	0		500	ns
		V _{CC} = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vee	Т	A = 25°C	;	SN54HC4020		SN74HC4020		UNIT
PARAMETER	TEST CC	INDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
VOH	$V_I = V_{IH} \text{ or } V_{IL}$		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = -5.2 mA	6 V	5.48	5.8		5.2		5.34		
	V _{OL} V _I = V _{IH} or V _{IL}		2 V		0.002	0.1		0.1		0.1	
		I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
l	$V_{I} = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I ^O = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF



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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			N.	T _A = 2	25°C	SN54H	C4020	SN74H	C4020	UNIT
			vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	0	5.5	0	3.7	0	4.3	
f _{clock} Clock frequency			4.5 V	0	28	0	19	0	22	MHz
			6 V	0	33	0	22	0	25	
		CLK high or low	2 V	90		135		115		
	CLK high or Pulse duration CLR high		4.5 V	18		27		23		1
				6 V	15		23		20	
tw			2 V	70		105		90		115
		CLR high	4.5 V	14		21		18		
			6 V	12		18		25		
		•	2 V	60		90		75		
t_{SU} Setup time, CLR inactive before CLK \downarrow		.↓	4.5 V	12		18		15		ns
			6 V	10		15		13		

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то		Τį	λ = 25°C	;	SN54H	C4020	SN74H	C4020	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V	5.5	10		3.7		4.3			
fmax			4.5 V	28	45		19		22		MHz	
			6 V	33	53		22		25			
			2 V		62	150		225		190		
^t pd	CLK	QA	4.5 V		16	30		45		38	ns	
						6 V 12	26		38		32	
			2 V		63	140		210		175		
^t PHL	CLR	Any	4.5 V		17	28		42		35	ns	
				6 V		13	24		36		30	
		Any	2 V		28	75		110		95		
tt			4.5 V		8	15		22		19	ns	
			6 V		6	13		19		16		

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load	88	pF



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PARAMETER MEASUREMENT INFORMATION

- NOTES: A. CL includes probe and test-fixture capacitance.
 - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_Q = 50 Ω , t_f = 6 ns, t_f = 6 ns.
 - C. For clock inputs, fmax is measured when the input duty cycle is 50%.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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